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# SIMULATION OF DOUBLE JUNCTION IN IRRADIATED DETECTORS USING SILVACO TCAD

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# Simulation Task

The set of parameters for cross-test simulation:

**Detector thickness** -----  $d=0.03$  cm

**Concentration of shallow donors (phosphorus)** -----  $N_{SD} = 6e11$  cm<sup>-3</sup>

**Bulk generated current calculated from**

**2- level trap model**

Type of defect	Activation energy, eV	Trapping cross section, cm <sup>2</sup>	Introduction rate, cm <sup>-1</sup>
Deep donor	$E_{DD} - E_V = 0.48$	$\sigma_e = \sigma_h = 1e-15$	$G_{DD} = 1$
Deep acceptor	$E_{DA} - E_V = 0.595$	$\sigma_e = \sigma_h = 1e-15$	$G_{DA} = 1$

**Bulk generated current calculated from** **Not available in simulation**

Single level model

Effective energy of current generating level-----  $E_j - 0.65$  eV

Effective cross-section of current generating level -----  $s_j = 1e-13$ cm<sup>2</sup>

Introduction rate of current generating level -----  $G_j = 1$  cm<sup>-1</sup>

Simulations are compared for:

$T = 290K$  and  $260K$

$V = 200V, 300V, 500V, 1000V$  at  $F = 1e15$ cm<sup>-2</sup>

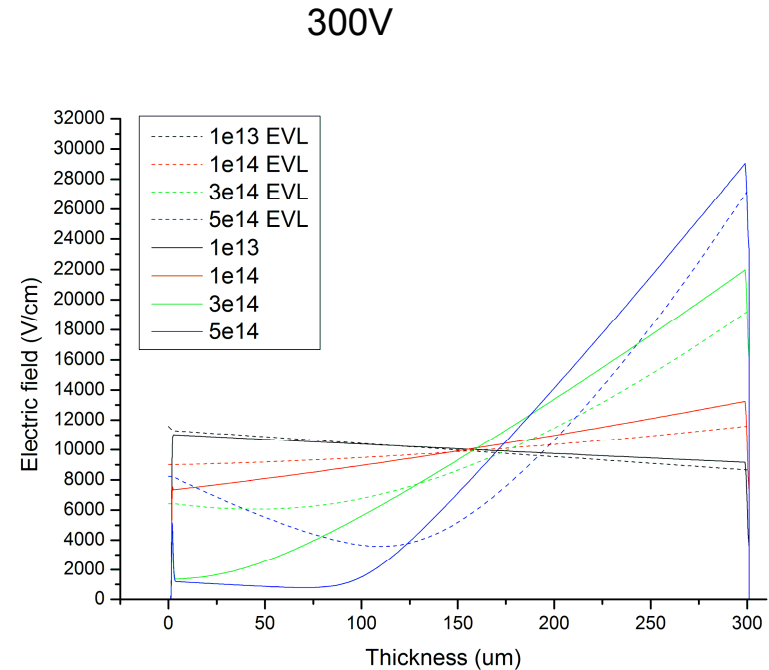
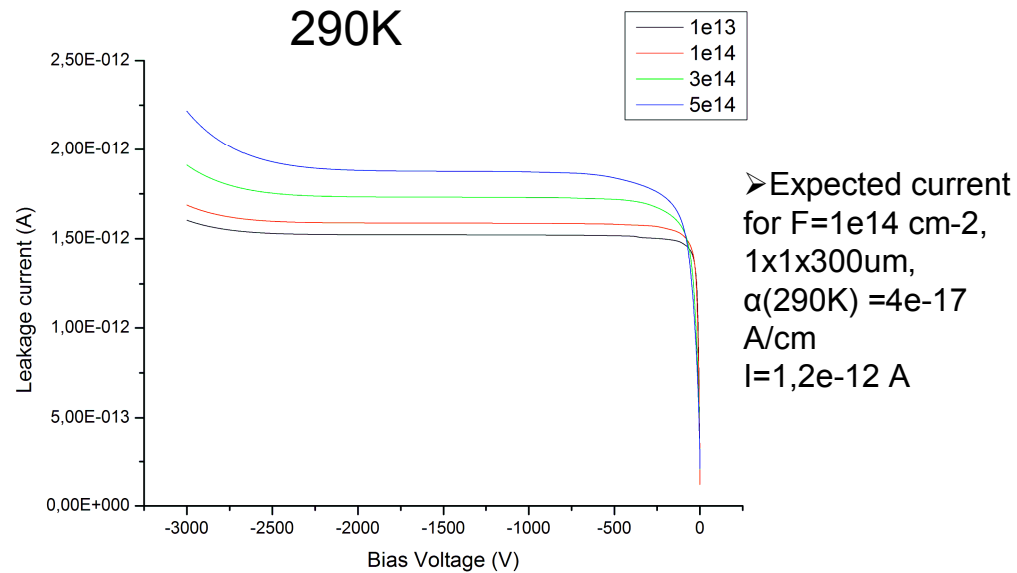
$F = 1e13, 1e14, 3e14, 1e15, 3e15$  cm<sup>-2</sup> at  $V=300V$

# Original EVL defect model

- Simple detector  $1\mu\text{m} \times 1\mu\text{m} \times 300\mu\text{m}$
- Bulk doping  $[n\text{-bulk}] = 6 \times 10^{11} \text{ cm}^{-3}$
- $n+$ ,  $p+$  junction depth  $1\mu\text{m}$
- Silvaco TCAD (5.16.3.R)

➤  $I = \alpha \times F \times \text{Vol}$

- Rescaling of the energy levels:  
 Silvaco  $E_g = 1.08 \text{ eV}$   
 $E.\text{level silvaco} = E.\text{level} \times E_{g\text{silvaco}} / E_g$   
 $E_{\text{acceptor}} = 0.504 \text{ eV}$   
 $E_{\text{donor}} = 0.46 \text{ eV}$



- Does not match, decrease the current
- Tuning of the parameters

# Modified EVL

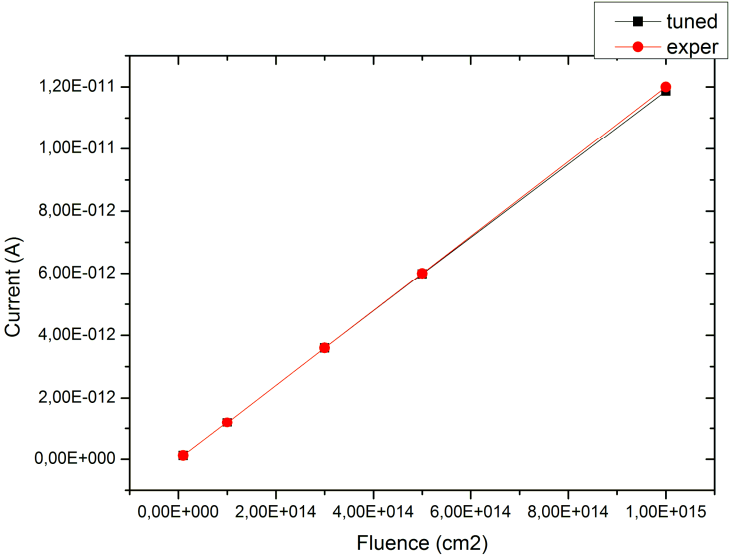
➤ EVL

Type of defect	Activation energy, eV	Trapping cross section, cm <sup>2</sup>	Introduction rate, cm <sup>-1</sup>
Deep donor	$E_{DD} - E_V = 0.48$	$\sigma_e = \sigma_h = 1e-15$	$G_{DD} = 1$
Deep acceptor	$E_{DA} - E_V = 0.595$	$\sigma_e = \sigma_h = 1e-15$	$G_{DA} = 1$



➤ Modified

Type of defect	Activation energy, eV	Trapping cross section, cm <sup>2</sup>	Introduction rate, cm <sup>-1</sup>
Deep donor	$E_{DD} - E_V = 0.48$	$\sigma_e = 4e-14 \quad \sigma_h = 1e-14$	$G_{DD} = 1.63$
Deep acceptor	$E_{DA} - E_V = 0.59$	$\sigma_e = 4e-14 \quad \sigma_h = 1e-14$	$G_{DA} = 1.63$



290K

➤ Good agreement of experimental value of current and modified simulation

# Modified EVL, 290K

## Simulations at 290K

Trap introduction rate=1.63

Acceptor( $\sigma_n = 4e-14 \text{ cm}^2$ ,  $\sigma_p = 1e-14 \text{ cm}^2$ ),

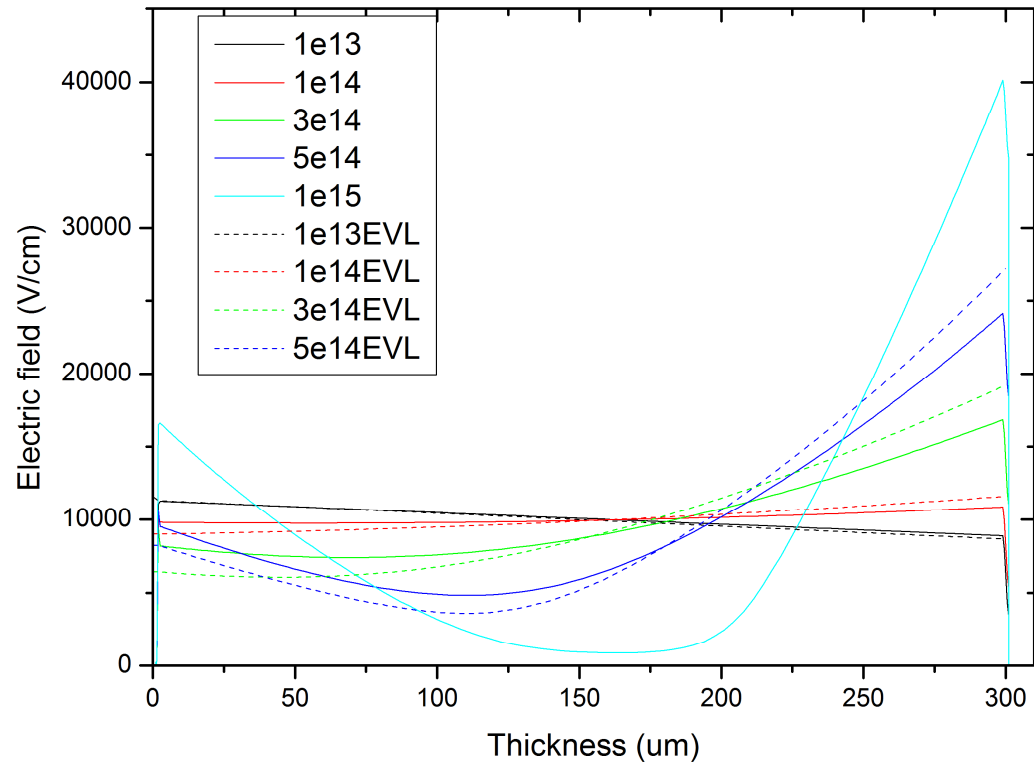
Donor ( $\sigma_n = 4e-14 \text{ cm}^2$ ,  $\sigma_p = 1e-14 \text{ cm}^2$ )

$\tau_0 = 1e-3 \text{ sec}$

300V

➤ Activation energies as in EVL model

➤ Good agreement



# Modified EVL, 290K

$F=5e14 \text{ cm}^{-2}$

## Simulations at 290K

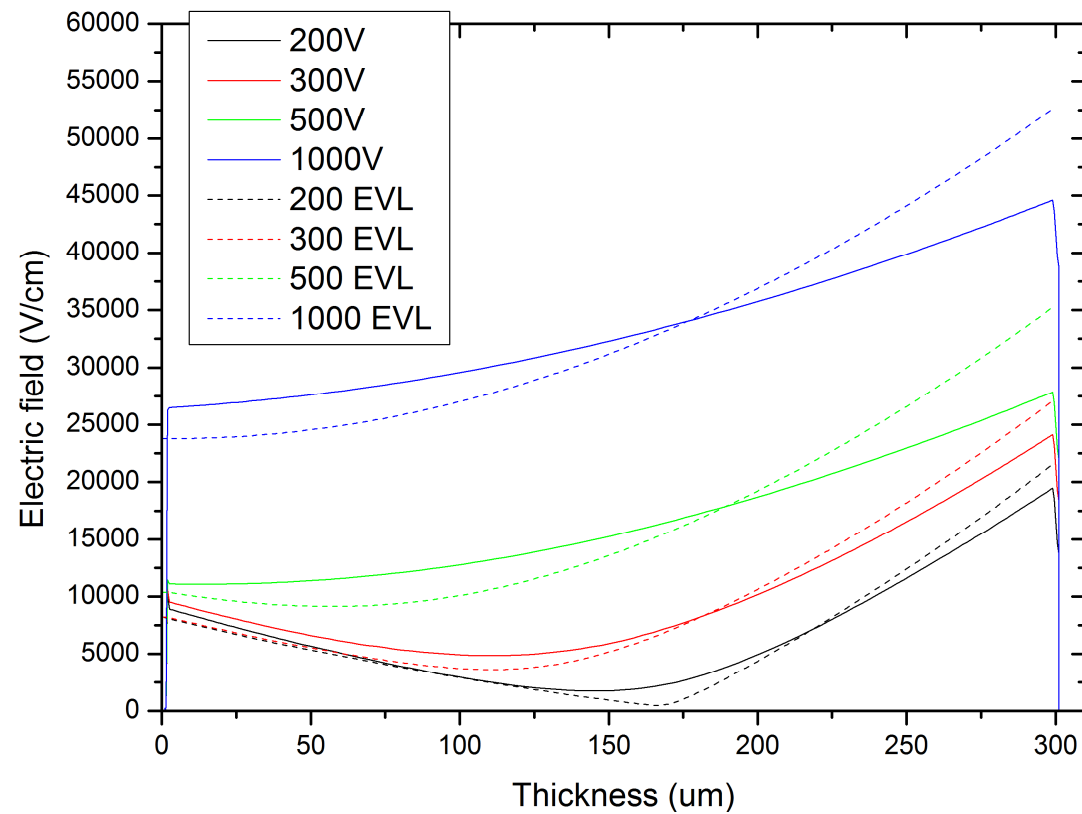
Trap introduction rate=1.63

Acceptor ( $\sigma_n = 4e-14 \text{ cm}^2$ ,  $\sigma_p = 1e-14 \text{ cm}^2$ ),

Donor ( $\sigma_n = 4e-14 \text{ cm}^2$ ,  $\sigma_p = 1e-14 \text{ cm}^2$ )

$\tau_0 = 1e-3 \text{ sec}$

➤ Activation energies as in EVL model

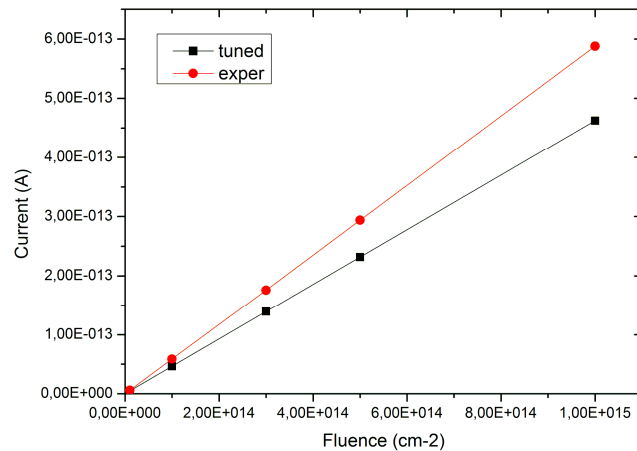


# Modified EVL, 260K

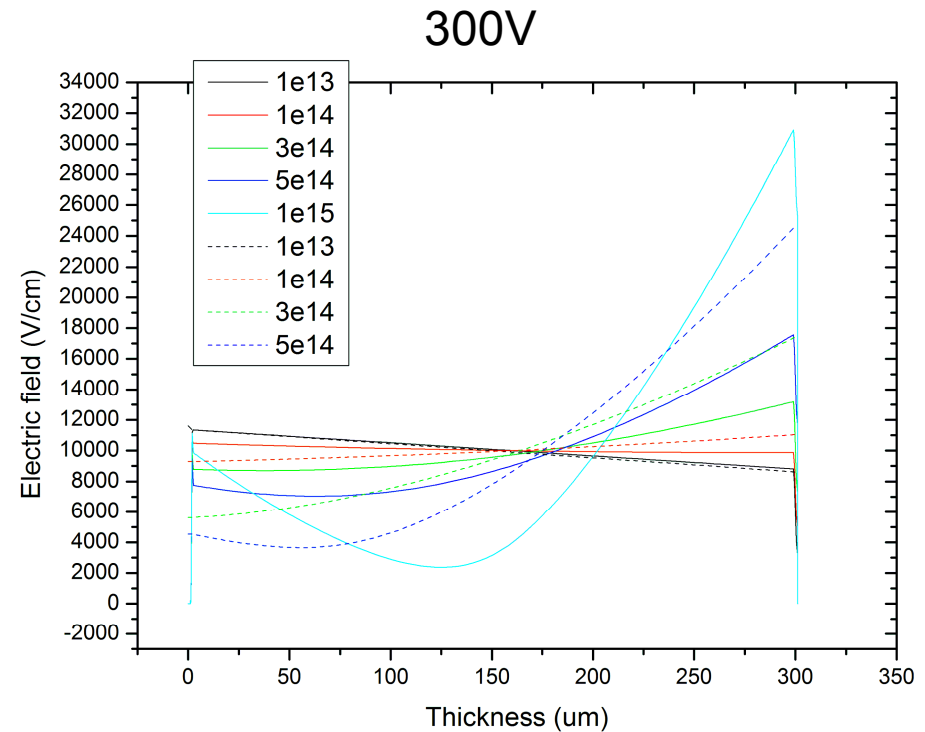
## Simulations at 260K

Trap introduction rate=1.63  
Acceptor( $\sigma_n = 4e-14$ ,  $\sigma_p = 1e-14$ ),  
Donor ( $\sigma_n = 4e-14$ ,  $\sigma_p = 1e-14$ )  
 $\tau_0 = 1e-3$  sec

➤ Activation energies as in EVL model



$\alpha(260K) = 1.96e-18$  A/cm



➤ Less number of traps are activated

# Modified EVL, 260K

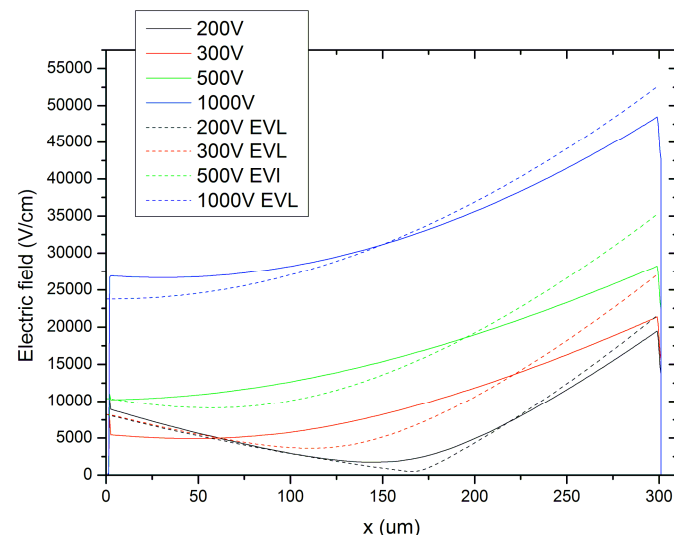
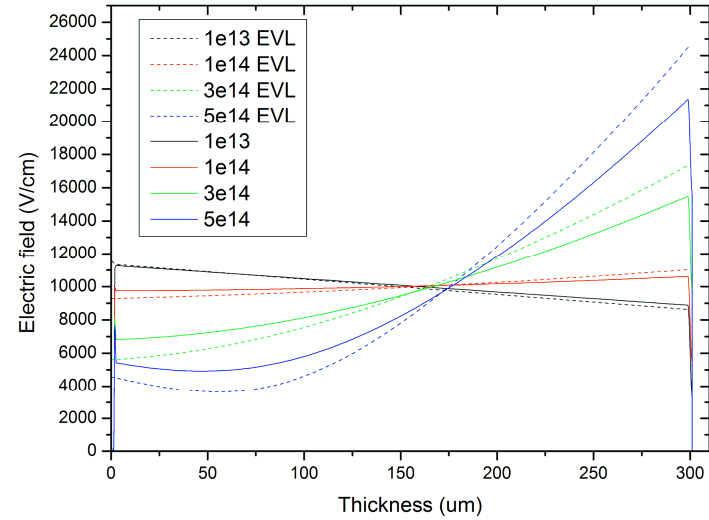
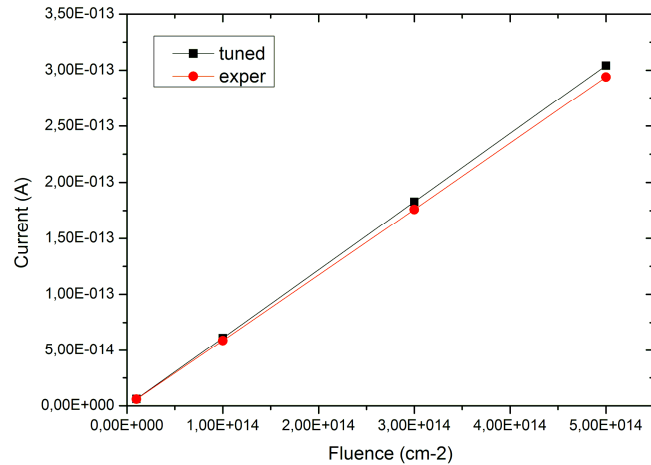
## Simulations at 260K

Trap introduction rate=1.43

Acceptor ( $\sigma_n = 3e-14$ ,  $\sigma_p = 1.5e-14$ ),

Donor ( $\sigma_n = 3e-14$ ,  $\sigma_p = 1.5e-14$ )

$\tau_0 = 1e-3$  sec





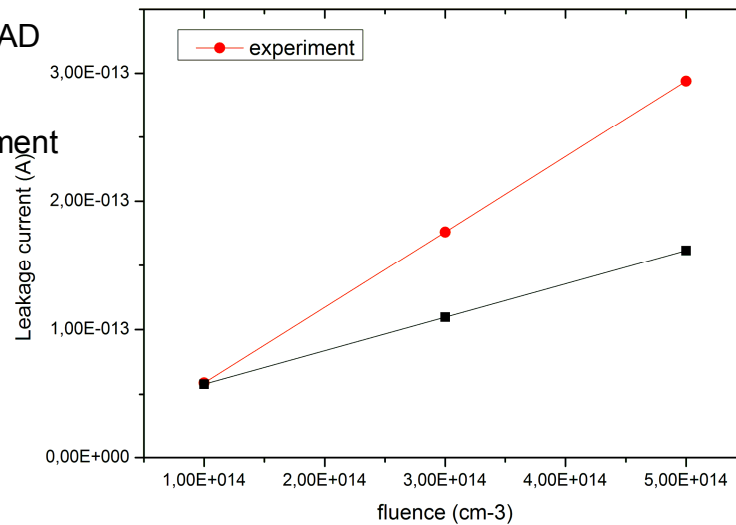
# EVL defect model, tuned by Robert Eber, KIT

253K

Type of defect	Activation energy, eV	Trapping cross section, cm <sup>2</sup>	Introduction rate, cm <sup>-1</sup>	Acceptor/donor conc., cm <sup>-3</sup>
Deep acceptor	$E_c - E_{DA} = 0.525$	$se = sh = 1e-14$	GDA = 1.189	$1.189 * F + 6.454e13$
Deep donor	$E_v + E_{DD} = 0.48$	$se = sh = 1e-14$	GDD = 5.598	$5.598 * F - 3.959e14$

➤ Silvaco TCAD

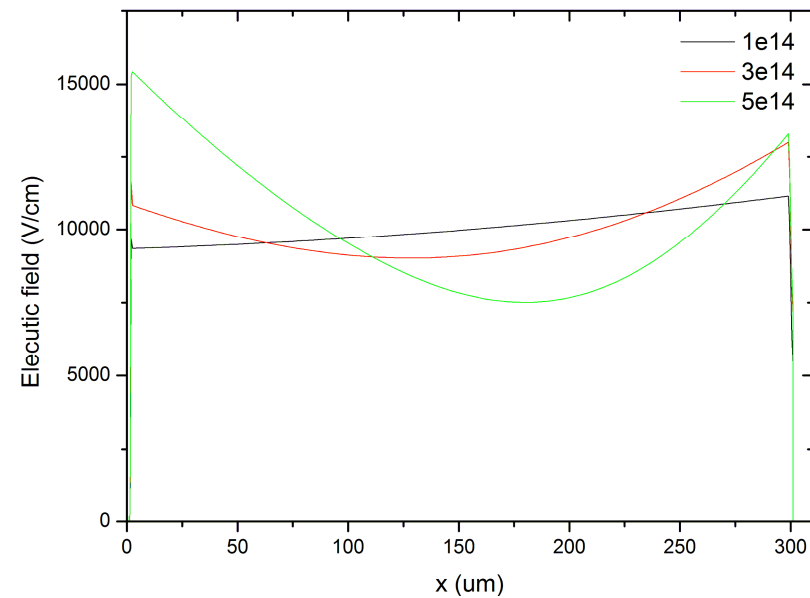
➤ No agreement in current



➤  $\alpha(253K) = 8.8e-19$  A/cm

➤ No inversion

253K, 300V



# Summary

- Tuning of the defect parameters is a good way to modify EVL-model
- For  $T=290\text{K}$  good agreement achieved by increasing of the introduction rate to  $1.63 \text{ 1/cm}$ , decreasing the ratio of the hole and electron cross section to 0.25.
- It seems that Robert Eber's model doesn't work in Silvaco as good as in Synopsys